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- 12 A Continuous On-State Current
- 100 A Surge-Current
- Glass Passivated Wafer
- 400 V to 800 V Off-State Voltage
- Max I<sub>GT</sub> of 20 mA



Pin 2 is in electrical contact with the mounting base.

MDC1ACA

### absolute maximum ratings over operating case temperature (unless otherwise noted)

RATING	SYMBOL	VALUE	UNIT		
	TIC126D		400		
Repetitive peak off-state voltage (see Note 1)	TIC126M	V	600	V	
Trepennive pear on-state vonage (see Note T)	TIC126S	V <sub>DRM</sub>	700	v	
	TIC126N		800		
	TIC126D		400		
Denstitive neek reverse veltere	TIC126M	N/	600	V	
Repetitive peak reverse voltage	TIC126S	V <sub>RRM</sub>	700	v	
	TIC126N		800		
Continuous on-state current at (or below) 80°C case temperature (see Note 2)			12	А	
Average on-state current (180° conduction angle) at (or below) 80°C case temperature			7.5	А	
(see Note 3)			7.5	А	
Surge on-state current (see Note 4)			100	А	
Peak positive gate current (pulse width $\leq$ 300 µs)			3	А	
Peak gate power dissipation (pulse width $\leq 300 \ \mu$ s)			5	W	
Average gate power dissipation (see Note 5)			1	W	
Operating case temperature range			-40 to +110	°C	
Storage temperature range			-40 to +125	°C	
Lead temperature 1.6 mm from case for 10 seconds			230	°C	

NOTES: 1. These values apply when the gate-cathode resistance  $R_{GK}$  = 1 k\Omega.

2. These values apply for continuous dc operation with resistive load. Above 80°C derate linearly to zero at 110°C.

3. This value may be applied continuously under single phase 50 Hz half-sine-wave operation with resistive load. Above 80°C derate linearly to zero at 110°C.

4. This value applies for one 50 Hz half-sine-wave when the device is operating at (or below) the rated value of peak reverse voltage and on-state current. Surge may be repeated after the device has returned to original thermal equilibrium.

5. This value applies for a maximum averaging time of 20 ms.



APRIL 1971 - REVISED MARCH 1997

### electrical characteristics at 25°C case temperature (unless otherwise noted)

PARAMETER			TEST CONDITIO	NS	MIN TYP M			IAX UNIT
I <sub>DRM</sub>	Repetitive peak off-state current	$V_{D}$ = rated $V_{DRM}$	$R_{GK}$ = 1 k $\Omega$	T <sub>C</sub> = 110°C			2	mA
I <sub>RRM</sub>	Repetitive peak reverse current	$V_R$ = rated $V_{RRM}$	$I_{\rm G}=0$	T <sub>C</sub> = 110°C			2	mA
I <sub>GT</sub>	Gate trigger current	V <sub>AA</sub> = 6 V	$R_L = 100 \Omega$	$t_{p(g)} \ge 20 \ \mu s$		5	20	mA
V <sub>GT</sub>	Gate trigger voltage	$V_{AA} = 6 V$ $t_{p(g)} \ge 20 \ \mu s$	R <sub>L</sub> = 100 Ω R <sub>GK</sub> = 1 kΩ	$T_C = -40^{\circ}C$			2.5	
		V <sub>AA</sub> = 6 V t <sub>p(g)</sub> ≥ 20 µs	R <sub>L</sub> = 100 Ω R <sub>GK</sub> = 1 kΩ			0.8	1.5	V
		V <sub>AA</sub> = 6 V t <sub>p(g)</sub> ≥ 20 µs	R <sub>L</sub> = 100 Ω R <sub>GK</sub> = 1 kΩ	T <sub>C</sub> = 110°C	0.2			
Ι <sub>Η</sub>	Holding current	$V_{AA} = 6 V$ Initiating I <sub>T</sub> = 100 mA	$R_{GK} = 1 \ k\Omega$	$T_{C} = -40^{\circ}C$			70	mA
		$V_{AA} = 6 V$ Initiating I <sub>T</sub> = 100 mA	$R_{GK} = 1 \ k\Omega$				40	110 (
$V_{TM}$	Peak on-state voltage	I <sub>TM</sub> = 12 A	(see Note 6)				1.4	V
dv/dt	Critical rate of rise of off-state voltage	$V_D$ = rated $V_D$	$I_{G} = 0$	$T_{\rm C} = 110^{\circ}{\rm C}$		100		V/µs

NOTE 6: This parameter must be measured using pulse techniques,  $t_p = 300 \ \mu$ s, duty cycle  $\le 2 \ \%$ . Voltage sensing-contacts, separate from the current carrying contacts, are located within 3.2 mm from the device body.

### thermal characteristics

PARAMETER			TYP	MAX	UNIT
R <sub>θJC</sub>	Junction to case thermal resistance			2.4	°C/W
$R_{ extsf{ heta}JA}$	Junction to free air thermal resistance			62.5	°C/W

### resistive-load-switching characteristics at 25°C case temperature

	PARAMETER	TEST CONDITIONS			MIN	TYP	MAX	UNIT
t <sub>gt</sub>	Gate-controlled turn-on time	I <sub>T</sub> = 5 A	l <sub>G</sub> = 200 mA	See Figure 1		0.8		μs
t <sub>q</sub>	Circuit-commutated turn-off time	I <sub>T</sub> = 5 A	I <sub>RM</sub> = 10 A	See Figure 2		11		μs

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Figure 2. Circuit-commutated turn-off time

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## **TYPICAL CHARACTERISTICS**

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### **TYPICAL CHARACTERISTICS**

Figure 10.



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### **TYPICAL CHARACTERISTICS**



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## **MECHANICAL DATA**

## **TO-220**

### 3-pin plastic flange-mount package

This single-in-line package consists of a circuit mounted on a lead frame and encapsulated within a plastic compound. The compound will withstand soldering temperature with no deformation, and circuit performance characteristics will remain stable when operated in high humidity conditions. Leads require no additional cleaning or processing when used in soldered assembly.



B. Mounting tab corner profile according to package version.

Typical fixing hole centre stand off height according to package version. C.





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